## Applicant(s)/Patent Under Application/Control No. Reexamination 10/821,868 PIHLAJAMAA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2617 Michael T. Thier **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α US-В US-С US-D US-Е US-F US-G US-Н US-١ US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS

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